Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/810,440	MATSUI ET AL.
Examiner	Art Unit
Yong D. Pak	1652

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Class	Subclass	Date	Examiner
435	193	8/10/2005	ΥP
435	106	8/10/2005	YP
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH N (INCLUDING SEARC	NOTES CH STRATEGY	)
	DATE	EXMR
stic: seq id no:1	8/10/2005	YP
stn/east: see search history	8/10/2005	YP
Inventor search	8/10/2005	YP